

EMC TEST REPORT

According to

- 1) EN 55022: 1998+A1: 2000
- 2) EN 61000-3-2: 2000
- 3) EN 61000-3-3: 1995+A1: 2001
- 4) EN 55024: 1998+A1: 2001
EN 61000-4-2: 1995+A2: 2001 / EN 61000-4-3: 1996+A2: 2001
EN 61000-4-4: 1995+A2: 2001 / EN 61000-4-5: 1995+A1: 2001
EN 61000-4-6: 1996+A1: 2001 / EN 61000-4-8: 1993+A1: 2001
EN 61000-4-11: 1994+A1: 2001

EUT Name : USB Serial Adapter

Model No. : AP1100

Applicant : GOOD WAY TECHNOLOGY CO., LTD.

3F, NO. 135, LANE 235, PAU CHIAO RD., HSIN TIEN,
TAIPEI COUNTY, TAIWAN, R. O. C.

Test Engineer : STEVEN CHEN

Reviewed by : BARRY MA

Issued Date: : SEP. 14, 2004

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- The report can't be used by the client to claim product endorsement by PEP Testing Laboratory.
- This report is only for the equipment which described in page 7.

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1. General

1.1 General Information :

Applicant : GOOD WAY TECHNOLOGY CO., LTD.

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TAIPEI COUNTY, TAIWAN, R. O. C.

Manufacturer : GOOD WAY TECHNOLOGY CO., LTD.

3F, NO. 135, LANE 235, PAU CHIAO RD., HSIN TIEN,
TAIPEI COUNTY, TAIWAN, R. O. C.

Measurement Procedure : EN55022

1.2 Place of Measurement

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NVLAP LAB CODE 200097-0

FCC Registration No. : 90868

NEMKO Aut. No. : ELA133

BSMI Aut. No. : SL2-IN-E-11

VCCI Registration No. : C-493/R-477

1.3 Test Standards

Tested for compliance with:

- | | |
|----------------------------|---|
| EN 55022:1998 | - Information Technology Equipment – Radio disturbance characteristics - Limits and methods of measurement |
| +A1: 2000 | |
| EN 61000-3-2: 2000 | - Electromagnetic compatibility (EMC) Part 3-2: Limits – Limits for harmonic current emissions (equipment input Current up to and including 16A per phase |
| EN 61000-3-3: 1995 | - Electromagnetic compatibility (EMC) Part 3-2: Limits – |
| +A1: 2001 | Limitation of voltage fluctuations and flicker in low-voltage supply systems for equipment with rated current up to 16A |
| EN 55024:1998 | - Information technology equipment – Immunity characteristics |
| +A1: 2001 | Limits and methods of measurement |
| EN 61000-4-2: 1995 | - Electromagnetic compatibility (EMC) Part 4: Testing and measurement techniques, Section 2: Electrostatic discharge immunity test Basic EMC Publication |
| +A2: 2001 | |
| EN 61000-4-3: 1996 | - Electromagnetic compatibility (EMC) Part 4: Testing and measurement techniques, Section 3: Radiated, radio- |
| +A2: 2001 | Frequency, electromagnetic field immunity test |
| EN 61000-4-4: 1995 | - Electromagnetic compatibility (EMC) Part 4: Testing and measurement techniques, Section 4: Electrical fast transient / Burst immunity test Basic EMC publication |
| +A2: 2001 | |
| EN 61000-4-5: 1995 | - Electromagnetic compatibility (EMC) Part 4: Testing and measurement techniques, Section 5: Surge immunity test (includes corrigendum: 1995) |
| +A1: 2001 | |
| EN 61000-4-6: 1996 | - Electromagnetic compatibility (EMC) Part 4: Testing and measurement techniques, Section 6: Immunity to conducted disturbances, induced by radio-frequency fields |
| +A1: 2001 | |
| EN 61000-4-8: 1993 | - Electromagnetic compatibility (EMC) Part 4: Testing and measurement techniques, Section 8: Power frequency magnetic field immunity test Basic EMC publication |
| +A1: 2001 | |
| EN 61000-4-11: 1994 | - Electromagnetic compatibility (EMC) Part 4: Testing and measurement techniques, Section 11: Voltage dips, short interruptions and voltage variations immunity tests |
| +A1: 2001 | |

2. Product Information

- a. **EUT Name:** USB Serial Adapter
- b. **Model No. :** AP1100
- c. **CPU Type :** N/A
- d. **CPU Frequency :** N/A
- e. **Crystal/Oscillator(s) :** 12 MHz
- f. **Port/Connector(s) :** USB Connector * 1, RS232 Port * 1
- g. **Memory Expansion :** N/A
- h. **Power Rating :** DC 5V ----- From PC USB Port
- i. **Chassis Used :** ABS
- j. **Condition of the EUT :** Prototype Sample Engineering Sample
 Production Sample
- k. **Test Item Receipt Date :** SEP. 08, 2004

2a. Product Technical Judgement

N/A

3. EUT Description and Test Conclusion

The equipment under test (EUT) is USB Serial Adapter model AP1100. The EUT is data cable designed for the application of communicating USB interface and RS232 interface devices. DC 5V from PC power system is required to operate EUT. For more detail specification about the EUT, please refer to the user's manual.

Test method: According to the major function designed, the EUT configuration was set up by the following steps for test.

(A) Connect EUT USB connector to PC USB port.

(B) Connect EUT serial connector to modem.

All corresponding peripherals to PC I/O ports and EUT were set to proceed with test. The test was carried out on EUT operational condition and the worst-case test result was recorded and provided in this report.

Conducted emission test:

The system was setup with the EMI diagnostic software running. The power line conducted EMI tests were run on the line and neutral conductors of the power cord and the results were recorded. The effect of varying the position of the interface cables has been investigated to find the worst-case configuration that produces maximum emission.

At the frequencies where the peak values of the emission exceeded the quasi-peak limit, the emissions were also measured with the quasi-peak detectors. The average detector also measured the emission either (A) quasi-peak values were under quasi-peak limit but exceeded average limit, or (B) peak values were under quasi-peak limit but exceeded average limit.

Radiated emission test:

The maximum readings were found by varying the height of antenna and then rotating the turntable. Both polarization of antenna, horizontal and vertical, are measured. The effect of varying the position of the interface cables has been investigated to find the configuration that produces maximum emission.

The highest emissions were also analyzed in details by operating the spectrum analyzer in fixed tuned quasi-peak mode to determine the precise amplitude of the emissions.

In addition, the following test standards are applicable for related tests being carried out on the same EUT configuration and operational condition kept during radiated emission test and conducted emission test:

EN 61000-3-2, EN 61000-3-3, EN 61000-4-2, EN 61000-4-3, EN 61000-4-4, EN 61000-4-5, EN 61000-4-6, EN 61000-4-8, and EN 61000-4-11.

4. Modification(s):

N/A

5. Test Software Used

- (A) EMITEST program that continuously generates a complete line of repeating “H” letter was the software used during test.

6. Support Equipment Used

1. Personal Computer (PC3)

CPU : Intel P4 Socket 478 1.6GHz
FCC ID : Declaration of Conformity(DoC)
Manufacturer : LEMEL
Model Number : LMIH1A2
Power Supply : Switching
Power Cord : Non-Shielded, Detachable, 1.8m
Data Cable : N/A

2. Keyboard (KBS1 PS/2)

FCC ID : E5XKB5121WTH0110
Manufacturer : BTC
Model Number : 5121W
Power Supply : +5Vdc from PS2 of PC
Power Cord : N/A
Data Cable : 1 > Shielded , Non-detachable,1.6m
2 > Back Shell : Metal

3. Monitor (MON1 15")

FCC ID : Declaration of Conformity(DoC)
Manufacturer : SAMSUNG
Model Number : 550S
Power Supply : Switching
Power Cord : Non-Shielded, Detachable, 1.8m
Data Cable : 1 > Shielded , Non-detachable,1.2m
2 > Back Shell : Metal

4. Printer (PRN1)

FCC ID : B94C2642X
Manufacturer : Hewlett-Packard
Model Number : C2642E
Power Supply : Linear, 30Vdc O/P
Power Cable : Non-Shielded , Detachable,1.8m
Data Cable : 1 > Shielded , Detachable,1.2m
2 > Back Shell : Metal

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5. Modem (MOD1) × 3

FCC ID : IFAXDM1414

Manufacturer : ACEEX

Model Number : 1414

Power Supply : Linear, 9Vac O/P

Power Cable : Non-Shielded , Detachable,1.7m

Data Cable : 1 > Shielded , Detachable,1m

2 > Back Shell : Metal

6. Mouse (MOUS/1 PS/2)

FCC ID : DZL211106

Manufacturer : LOGITECH

Model Number : M-S43

Power Supply : +5Vdc from PS2 of PC

Power Cord : N/A

Data Cable : 1 > Shielded , Non-detachable,1.8m

2 > Back Shell : Metal

7. EN 55022 Conducted Disturbance Test

Test Standard	Model No.	Result
EN 55022	AP1100	Passed

7.1 Conducted Disturbance Test Limits at Main Ports

Frequency Rang	Limits dB(uV)			
	Class A ITE		Class B ITE	
MHz	Quasi-peak	Average	Quasi-peak	Average
0.15 - 0.50	79	66	66-56	56-46
0.50 - 5.0	73	60	56	46
5.0 - 30	73	60	60	50

Remarks: - If the average limit is met when a quasi-peak detector is used, the EUT shall be deemed to meet both limits and measurement with the average detector is unnecessary.

- The lower limit shall apply at the transition frequency

- The limit decreases linearly with the logarithm of the frequency in the range 0.15MHz to 0.50 MHz.

7.2 Conducted Disturbance Test Setup Photos

< FRONT VIEW >



< REAR VIEW >



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7.3 Conducted Disturbance Test Data at Main Ports (LISN)

Model No. : AP1100
Frequency range : 150KHz to 30MHz
Detector : Quasi-peak Value
Temperature : 27 °C
Humidity : 62 %

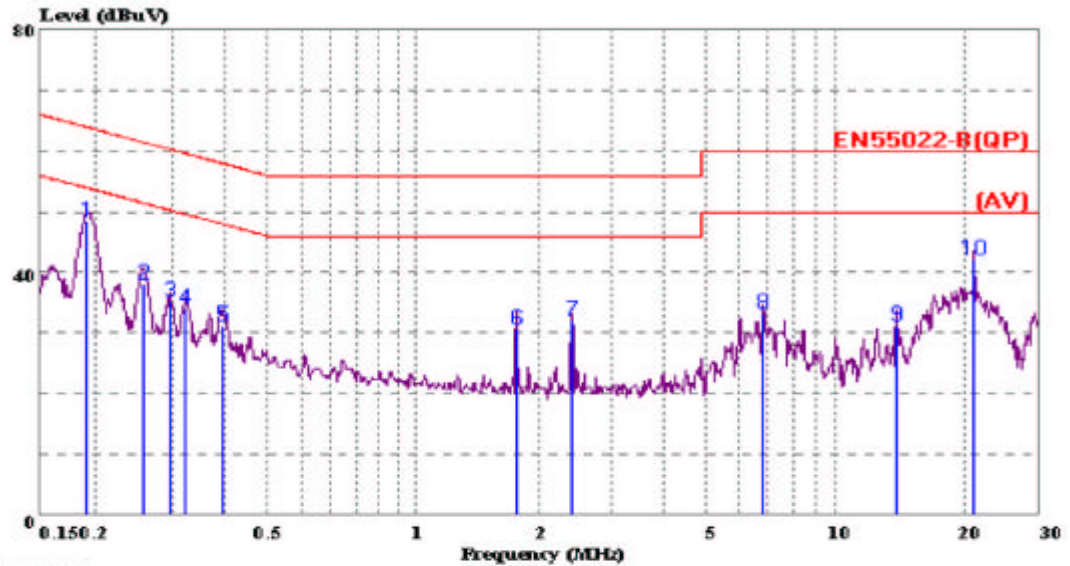
Test Data : # 466 < LINE >
465 < NEUTRAL >

- Note
1. Level = Read Level + Probe (LISN) Factor + Cable Loss
 2. Over Limit = Level – Limit Line = Margin



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Data#: 466 File#: EN55022-B(QP).EMI Date: 2004-09-09 Time: 14:11:54



Trace: 442

Site : Conduction No.2(Mick)-Linko site
 Condition: EN55022-B(QP) LISN.L(32A) LINE
 eut : E930592
 power : AC 230V/50Hz
 memo : Quasi peak Value

Page: 1

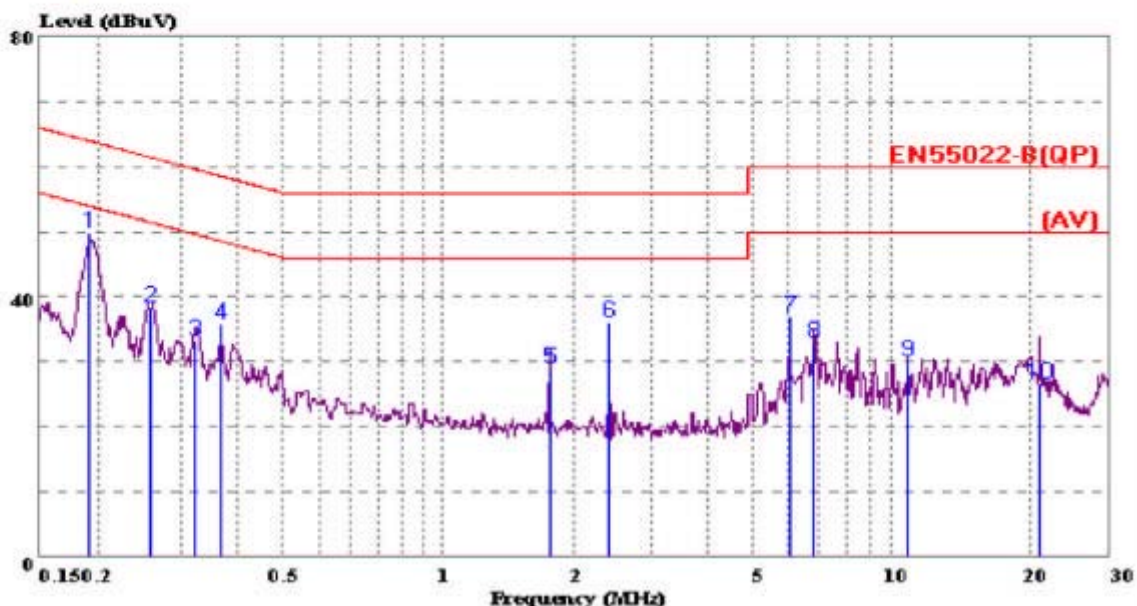
	Freq	Level	Over	Limit	Read	Probe	Cable	Remark
	MHz	dBuV	Limit	Line	Level	Factor	Loss	
			dB	dBuV	dBuV	dB	dB	
1	0.192	48.56	-15.37	63.93	48.40	0.10	0.06	QP
2	0.259	38.26	-23.21	61.47	38.00	0.14	0.12	QP
3	0.297	35.16	-25.16	60.32	34.85	0.16	0.15	QP
4	0.325	34.14	-25.43	59.57	33.82	0.17	0.15	QP
5	0.393	31.22	-26.77	57.99	30.87	0.20	0.15	QP
6	1.868	30.57	-25.43	56.00	30.07	0.20	0.30	QP
7	2.513	32.23	-23.77	56.00	31.69	0.20	0.34	QP
8	6.951	33.25	-26.75	60.00	32.53	0.26	0.46	QP
9	14.138	31.23	-28.77	60.00	29.92	0.64	0.67	QP
10	21.260	42.15	-17.85	60.00	40.47	0.90	0.78	QP



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Data#: 465 File#: EN55022-B(QP).EMI Date: 2004-09-09 Time: 14:20:31



Trace: 447
 Site : Conduction No.2(Mick)-Linko site
 Condition: EN55022-B(QP) LISN.N(32A) NEUTRAL
 eut : E930592
 power : AC 230V/50Hz
 memo : Quasi peak Value

Page: 1

	Freq	Level	Over Limit	Limit Line	Read Level	Probe Factor	Cable Loss	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB	dB	
1	0.192	49.76	-14.17	63.93	49.60	0.10	0.06	QP
2	0.260	38.55	-22.87	61.42	38.33	0.10	0.12	QP
3	0.325	33.12	-26.45	59.57	32.87	0.10	0.15	QP
4	0.367	35.92	-22.64	58.56	35.67	0.10	0.15	QP
5	1.878	28.95	-27.05	56.00	28.45	0.20	0.30	QP
6	2.513	36.14	-19.86	56.00	35.60	0.20	0.34	QP
7	6.153	36.95	-23.05	60.00	36.25	0.25	0.45	QP
8	6.951	32.88	-27.12	60.00	32.16	0.26	0.46	QP
9	11.080	30.08	-29.92	60.00	29.20	0.30	0.58	QP
10	21.147	26.76	-33.24	60.00	25.60	0.38	0.78	QP

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REPORT NO. : E930592

Model No. : AP1100
Frequency range : 150KHz to 30MHz
Detector : Average Value
Temperature : 29 °C
Humidity : 55 %

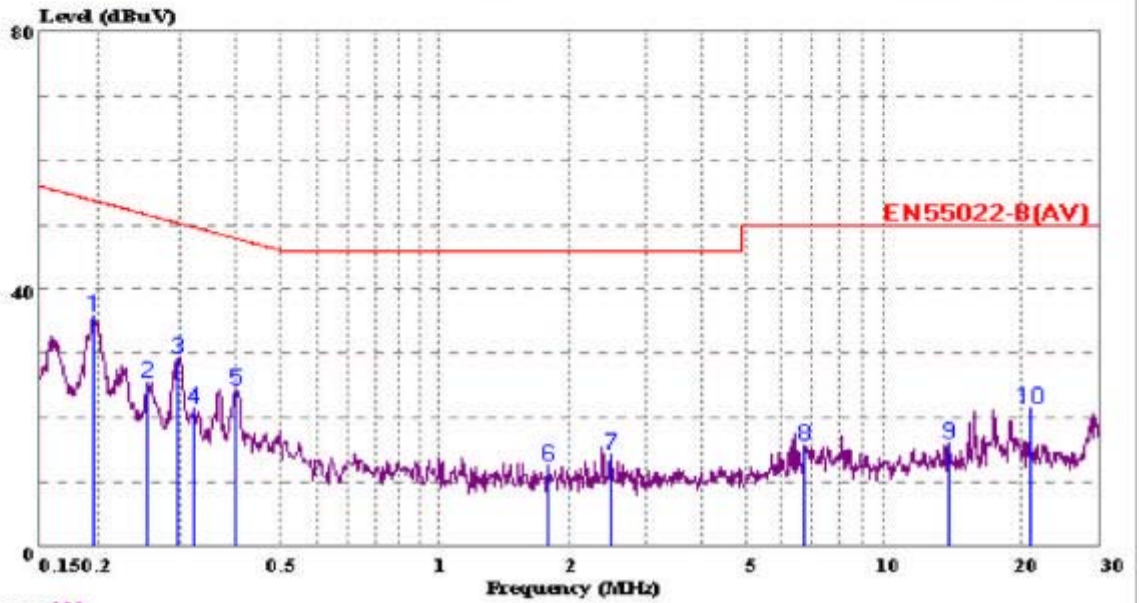
Test Data : # 203 < LINE >
198 < NEUTRAL >

- Note
1. Level = Read Level + Probe (LISN) Factor + Cable Loss
 2. Over Limit = Level – Limit Line = Margin



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Data#: 203 File#: EN55022-B(AV).EMI Date: 2004-09-09 Time: 14:31:15



Trace: 202
 Site : Conduction No.2(Mick)-Linko site
 Condition: EN55022-B(AV) LISN.L(32A) LINE
 eut : E930592
 power : AC 230V 50Hz
 memo : Average Value
 : \

Page: 1

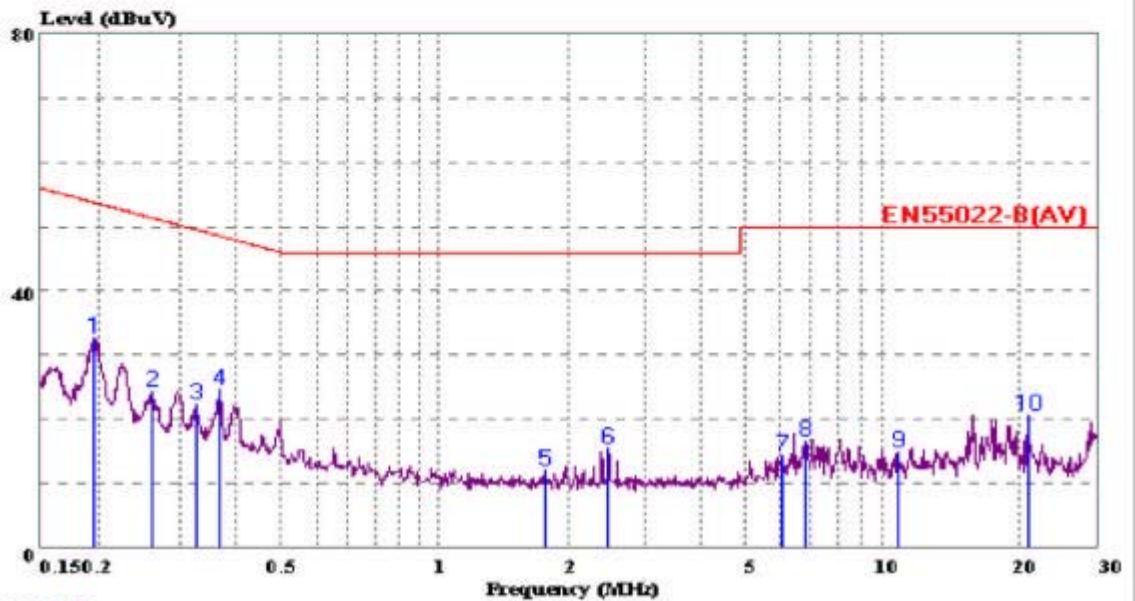
	Freq	Level	Over	Limit	Read	Probe	Cable	
	MHz	dBuV	Limit	Line	Level	Factor	Loss	Remark
			dB	dBuV	dBuV	dB	dB	
1	0.195	35.77	-18.03	53.80	35.61	0.10	0.06	
2	0.258	25.46	-26.05	51.51	25.20	0.14	0.12	
3	0.297	29.31	-21.01	50.32	29.00	0.16	0.15	
4	0.323	21.52	-28.10	49.62	21.20	0.17	0.15	
5	0.398	24.35	-23.55	47.90	24.00	0.20	0.15	
6	1.898	12.71	-33.29	46.00	12.20	0.20	0.31	
7	2.594	14.34	-31.66	46.00	13.80	0.20	0.34	
8	6.841	15.72	-34.28	50.00	15.00	0.26	0.46	
9	14.063	16.10	-33.90	50.00	14.81	0.63	0.66	
10	21.147	21.48	-28.52	50.00	19.80	0.90	0.78	



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Data#: 198 File#: EN55022-B(AV).EMI Date: 2004-09-09 Time: 14:27:22



Trace: 197
 Site : Conduction No.2(Mick)-Linko site
 Condition: EN55022-B(AV) LISN.N(32A) NEUTRAL
 eut : E930592
 power : AC 230V 50Hz
 memo : Average Value
 :

Page: 1

	Freq	Level	Over	Limit	Read	Probe	Cable	
	MHz	dBuV	Limit	Line	Level	Factor	Loss	Remark
			dB	dBuV	dBuV	dB	dB	
1	0.195	32.77	-21.03	53.80	32.61	0.10	0.06	
2	0.262	24.42	-26.96	51.38	24.20	0.10	0.12	
3	0.329	22.25	-27.24	49.49	22.00	0.10	0.15	
4	0.369	24.65	-23.87	48.52	24.40	0.10	0.15	
5	1.868	11.90	-34.10	46.00	11.40	0.20	0.30	
6	2.581	15.54	-30.46	46.00	15.00	0.20	0.34	
7	6.153	14.30	-35.70	50.00	13.60	0.25	0.45	
8	6.951	16.52	-33.48	50.00	15.80	0.26	0.46	
9	10.963	14.88	-35.12	50.00	14.00	0.30	0.58	
10	21.147	20.76	-29.24	50.00	19.60	0.38	0.78	

8. EN 55022 Radiated Disturbance Test

Test Standard	Model No.	Result
EN 55022	AP1100	Passed

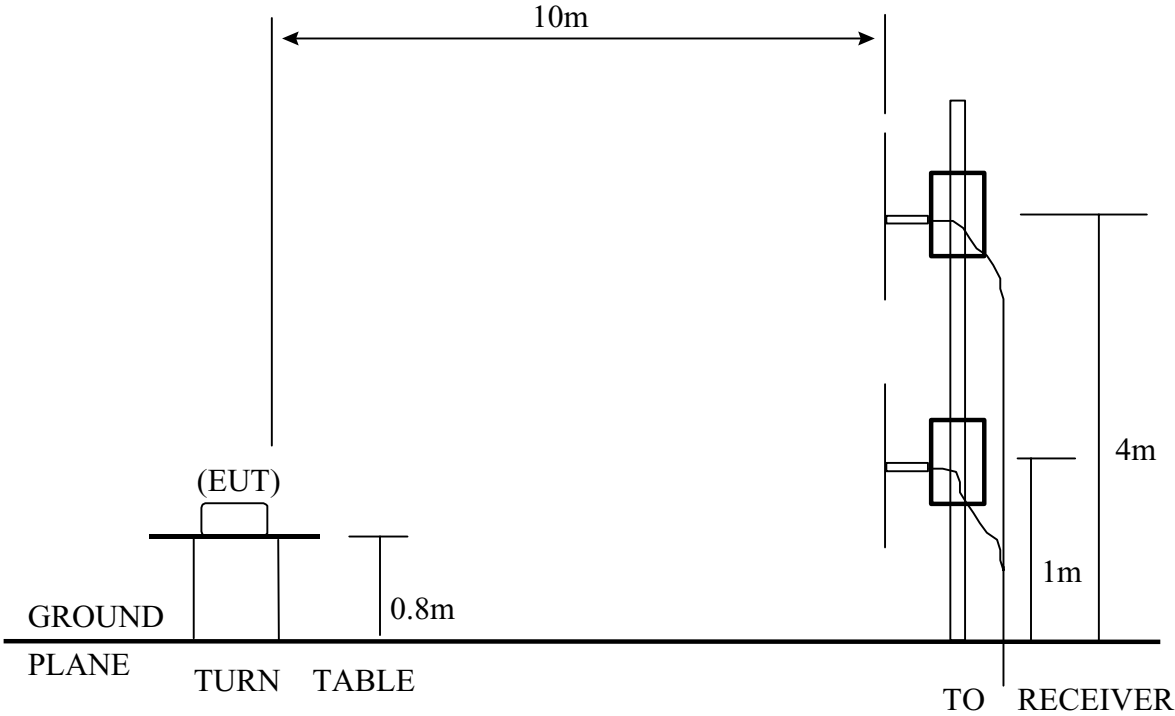
8.1 Radiated Disturbance Test Description

Preliminary measurements were made indoors chamber at 3 meter using broadband antennas, broadband amplifier, and spectrum analyzer to determine the frequency producing the maximum EME. Appropriate precaution was taken to ensure that all EME from the EUT were maximized and investigated. The system configuration, clock speed, mode of operation or video resolution, turntable azimuth with respect to the antenna were noted for each frequency found. The spectrum was scanned from 30 to 1000 MHz using logbicon antenna. Above 1GHz, linearly polarized double ridge horn antenna were used.

Final measurements were made outdoors at 10-meter test range using biconical, dipole antenna or horn antenna. The test equipment was placed on a wooden bench situated on a 1.5x1 meter area adjacent to the measurement area. Sufficient time for the EUT, support equipment, and test equipment was allowed in order for them to warm up to their normal operating condition. Each frequency found during pre-scan measurements was re-examined and investigated using Quasi-Peak Adapter. The detector function was set to CISPR quasi-peak mode and the bandwidth of the receiver was set to 120kHz.

The half-wave dipole antenna was tuned to the frequency found during preliminary radiated measurements. The EUT, support equipment and interconnecting cables were re-configured to the set-up producing the maximum emission for the frequency and were placed on top of a 0.8-meter high non-metallic 1 x 1.5 meter table. The EUT, support equipment, and interconnecting cables were re-arranged and manipulated to maximize each EME emission. The turntable containing the system was rotated; the antenna height was varied 1 to 4 meters and stopped at the azimuth or height producing the maximum emission.

8.2 Radiated Disturbance Test Setup



EUT = Equipment Under Test

8.3 Radiated Disturbance Test Limits

Limits for radiated disturbance of Class A ITE at
a measuring distance of 10 m

Frequency MHz	Field Strength dB(μ V/m)
30 to 230	40
230 to 1 000	47

NOTES

- 1 The lower limit shall apply at the transition frequency.
- 2 Additional provisions may be required for cases where interference occurs.

Limits for radiated disturbance of Class B ITE at
a measuring distance of 10 m

Frequency MHz	Field Strength dB(μ V/m)
30 to 230	30
230 to 1 000	37

NOTES

- 1 The lower limit shall apply at the transition frequency.
- 2 Additional provisions may be required for cases where interference occurs.

8.4 Radiated Disturbance Test Setup Photos

< FRONT VIEW >



< REAR VIEW >



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8.5 Radiated Disturbance Test Data

Model No. : AP1100
Frequency range : 30MHz to 1GHz **Detector** : Quasi-Peak Value
Temperature : 26 ° C **Humidity** : 68 %

Antenna polarization : HORIZONTAL ; **Test distance** : 10m ;

Freq. (MHz)	Level (dBuV/m)	Over Limit (dB)	Limit Line (dBuV/m)	Read Level (dBuV)	Antenna Factor (dB)	Cable Loss (dB)	Preamp Factor (dB)	Azimuth (angle)	Antenna High(m)
35.144	16.76	-13.24	30.00	24.30	10.97	1.09	19.60	136.0	4.0
116.189	20.17	- 9.83	30.00	25.88	11.81	1.97	19.49	271.0	4.0
134.383	19.79	-10.21	30.00	23.15	13.88	2.06	19.30	345.0	4.0
143.600	24.84	- 5.16	30.00	26.48	15.52	2.20	19.36	296.0	4.0
154.467	22.94	- 7.06	30.00	23.40	16.70	2.40	19.56	188.0	4.0
225.664	15.67	-14.33	30.00	20.69	11.28	2.90	19.20	210.0	3.3
366.671	23.61	-13.39	37.00	24.16	14.54	3.95	19.04	160.0	3.1

Note :

1. Level = Read Level + Antenna Factor + Cable Loss – Preamp Factor
2. Over Limit = Level – Limit Line

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REPORT NO. : E930592

Model No. : AP1100
Frequency range : 30MHz to 1GHz **Detector** : Quasi-Peak Value
Temperature : 26 ° C **Humidity** : 68 %

Antenna polarization : VERTICAL ; **Test distance** : 10m ;

Freq. (MHz)	Level (dBuV/m)	Over Limit (dB)	Limit Line (dBuV/m)	Read Level (dBuV)	Antenna Factor (dB)	Cable Loss (dB)	Preamp Factor (dB)	Azimuth (°angle)	Antenna High(m)
39.194	20.95	- 9.05	30.00	28.31	11.31	0.93	19.60	35.0	1.0
50.161	18.53	-11.47	30.00	26.23	10.70	1.20	19.60	166.0	1.0
71.978	23.38	- 6.62	30.00	34.07	7.31	1.56	19.56	19.0	1.0
134.344	16.26	-13.74	30.00	19.62	13.88	2.06	19.30	318.0	1.0
140.200	23.33	- 6.67	30.00	25.81	14.92	2.10	19.50	264.0	1.0
225.667	21.69	- 8.31	30.00	26.71	11.28	2.90	19.20	119.0	1.0
332.467	18.65	-18.35	37.00	20.43	13.72	3.67	19.17	140.0	1.5

Note :

1. Level = Read Level + Antenna Factor + Cable Loss – Preamp Factor
2. Over Limit = Level – Limit Line

9. EN 61000-3-2 Harmonic Current Test

Test standard	Model No.	Result
EN 61000-3-2	AP1100	Passed

9.1 Harmonic Current Test Description

The equipment under test is supplied in series with shunt(s) Rm or current transformer(s) from a source having the same nominal voltage and frequency as the rated supply voltage and frequency of the equipment under test. Whether the equipment operates with automatic, mixed or manual control, the measurements shall be made under normal load, or conditions for adequate heat discharge, and under normal operating conditions.

User's operation controls or automatic programmers shall be set to produce the maximum harmonic component, for each successive harmonic component in turn.

For the purpose of harmonic current limitation, equipment is classified as follows:

Class A:

- Balanced three-phase equipment;
- Household appliances excluding equipment identified as Class D;
- Tools excluding portable tools;
- Dimmers for incandescent lamps;
- Audio equipment.

Equipment not specified in one of the three other classes shall be considered as Class A equipment.

NOTE 1 Equipment that can be shown to have a significant effect on the supply system may be reclassified in a future edition of the standard. Factors to be taken into account include:

- number in use;
- duration of use;
- simultaneity of use;
- power consumption;
- harmonic spectrum, including phase.

Class B: Portable tools.

- Portable tools;
- Arc welding equipment which is not professional equipment.

Class C:

- Lighting equipment.

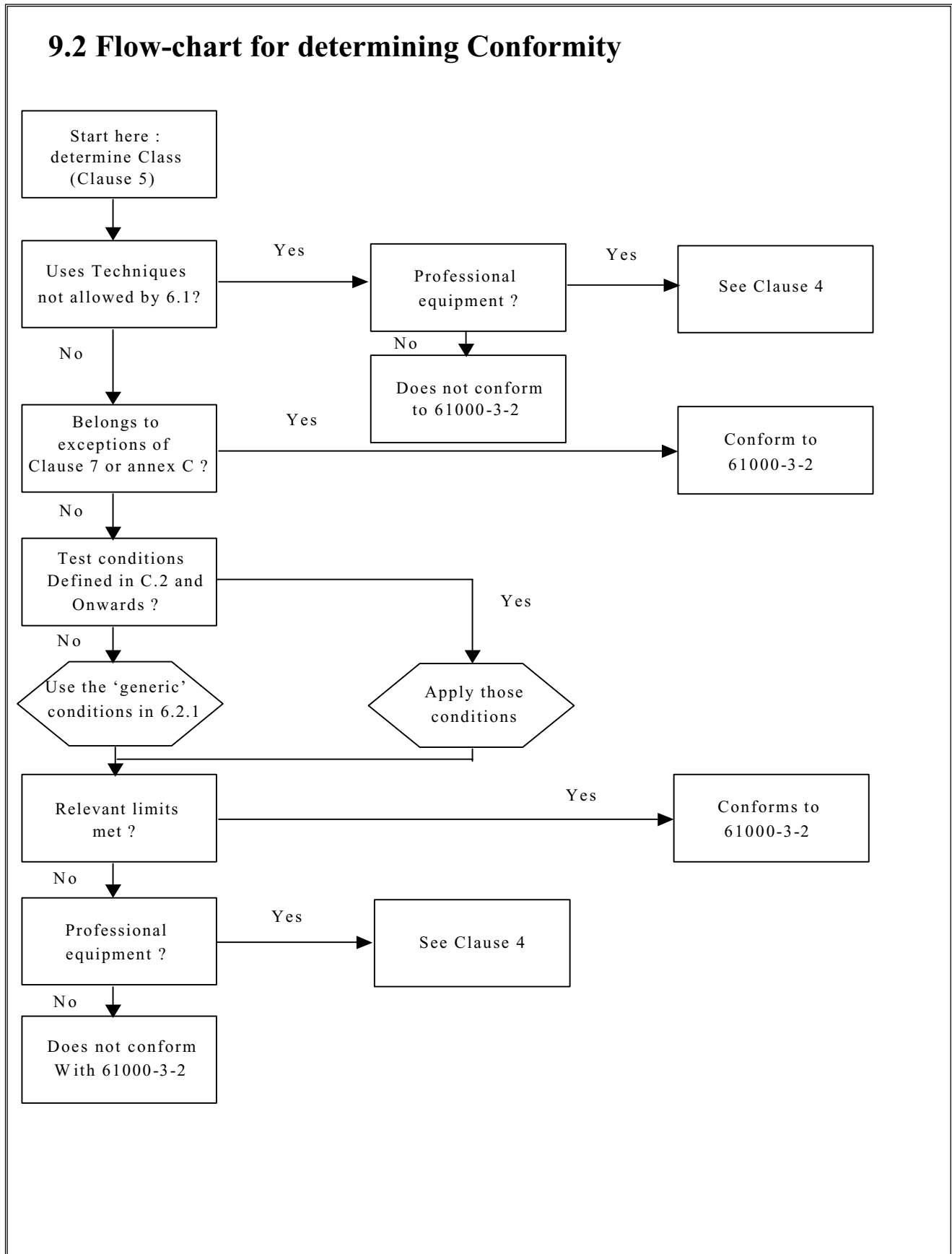
Class D:

Equipment having a specified power according to 6.2.2 less than or equal to 600W, of the following types:

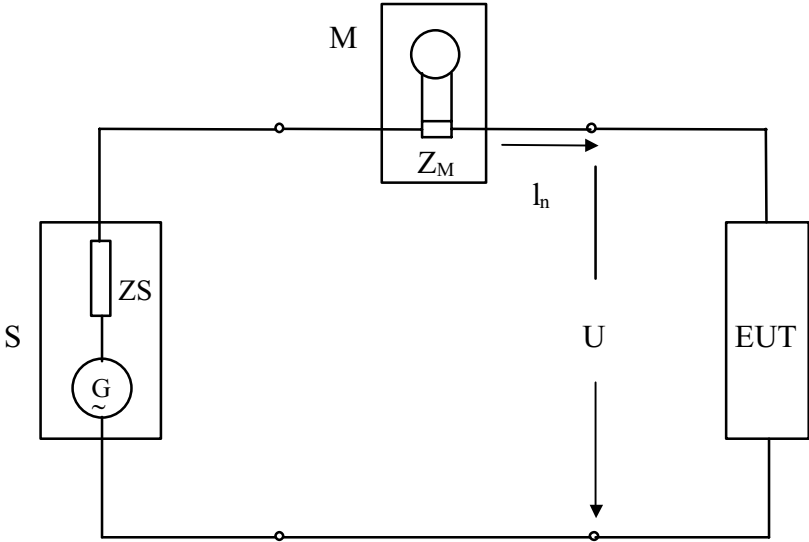
- Personal computers and personal computer monitors;
- Television receivers.

NOTE 2 Class D limits are reserved for equipment that, by virtue of the factors listed in note 1, can be shown to have a pronounced effect on the public electricity supply system.

9.2 Flow-chart for determining Conformity



9.3 Harmonic Current Test Setup



- | | | | |
|-----|-----------------------|-------|---|
| S | power supply source | Z_M | input impedance of measurement equipment |
| M | measurement equipment | Z_S | internal impedance of the supply source |
| EUT | equipment under test | I_n | harmonic component of order n of the line current |
| U | test voltage | G | open-loop voltage of the supply source |

9.4 Harmonic Current Test Limits

Table 1 Limits for Class A equipment

Harmonic order n	Maximum permissible harmonic current A
Odd harmonics	
3	2.30
5	1.14
7	0.77
9	0.40
11	0.33
13	0.21
15 ≤ n ≤ 39	0.15 $\frac{15}{n}$
Even harmonics	
2	1.08
4	0.43
6	0.30 $\frac{8}{n}$
8 ≤ n ≤ 40	0.23 $\frac{8}{n}$

Note :

1. For Class A equipment, the harmonics of the input current shall not exceed the absolute values given in table 1.
2. For Class B equipment, the harmonics of the input current shall not exceed the values given in table 1 multiplied by a factor of 1,5.

Table 2 Limits for Class C equipment

Harmonic order n	Maximum permissible harmonic current expressed as a percentage of the input current at the fundamental frequency %
2	2
3	$30 \cdot \lambda^*$
5	10
7	7
9	5
$11 \leq n \leq 39$ (odd harmonics only)	3

* λ is the circuit power factor

Note :

The harmonic current limits of lighting equipment shall not exceed the relative limits given in table 2.

Table 3 Limits for Class D equipment

Harmonic n	Maximum permissible harmonic current per watt mA/W	Maximum permissible harmonic current A
3	3.4	2.30
5	1.9	1.14
7	1.0	0.77
9	0.5	0.40
11	0.35	0.33
$13 \leq n \leq 39$ (odd harmonics only)	$\frac{3.85}{n}$	See table 1

Note :

The harmonics of the input current shall not exceed the values that can be derived from table 3.

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9.5 Harmonic Current Test Setup Photo

< FRONT VIEW >



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9.6 Harmonic Current Test Data

Model : AP1100
Line Voltage : 230.3 Vrms
RMS Current : 0.5 A
Real Power : 52.2 W
Fundamental Amp : 252.2 mArms
Line Frequency : 50 Hz
Device Class : A

Harm. Order	Indicated Values	Max. Permits Harm. Current Ampere
---	---	---
3	0.240	2.30
5	0.221	1.14
7	0.193	0.77
9	0.161	0.40
11	0.126	0.33
13	0.091	0.21
15	0.062	0.15
17	0.041	0.13
19	0.024	0.12
21	0.020	0.11
23	0.023	0.10
25	0.024	0.09
27	0.021	0.08
29	0.018	0.08
31	0.014	0.07
33	0.010	0.07
35	0.006	0.06
37	0.008	0.06
39	0.009	0.06

Harm. Order	Indicated Values	Max. Permits Harm. Current Ampere
2	0.005	1.08
4	0.005	0.43
6	0.004	0.30
8	0.003	0.23
10	0.002	0.18
12	0.002	0.15
14	0.002	0.13
16	0.002	0.12
18	0.002	0.10
20	0.001	0.09
22	0.001	0.08
24	0.001	0.08
26	0.001	0.07
28	0.001	0.07
30	0.000	0.06
32	0.001	0.06
34	0.001	0.05
36	0.001	0.05
38	0.000	0.05
40	0.000	0.05

10. EN 61000-3-3 Voltage Fluctuations Test

Test standard	Model No.	Result
EN 61000-3-3	AP1100	Passed

10.1 Voltage Fluctuations Test Description

EN 61000-3-3 standards define the measurement requirements, ac power source requirements, line impedance requirements, and voltage fluctuation and flicker limits for assessing electronic and electrical equipment's propensity to cause voltage disturbances on the ac mains. Compliance with these standards ensures that voltage fluctuations do not interfere with other equipment connected to the ac mains or cause incandescent lights to visibly flicker in a way that causes an annoyance or health risk to a human observer.

When automatic controls cycle on and off, they cause frequent changes of toehold to the supply. When the fluctuating load is in a branch circuit with other loads, these changes cause rms voltage fluctuations that affect all of the loads in the branch. In particular, variations in voltage amplitude cause changes in the light output of any filament lamps in the branch circuit. Because the output of a filament lamp is proportional to the square of the applied voltage, changes in light intensities can be significant even for small changes in voltage.

10.2 Voltage Fluctuations Test Limits

Compliance is determined if the following test parameters are within the following defined limits:

Short-term Flicker (Pst): The flicker severity evaluated over a short period of time (10 minutes). Pst = 1 is the conventional threshold of irritability, and therefore the limit.

Long-term Flicker (Plt): The flicker severity evaluated over a long period (typically 2 hours) using successive Pst values. Plt = 0.65 is the conventional threshold of irritability, and therefore the limit.

For voltage changes that are caused by manual switching of equipment or that occur less frequently than once per hour, Pst and Plt are not applicable.

However, the following voltage change “(D)” parameters are applicable, with the limits multiplied by 1.33.

Relative Steady-state Voltage Change (Dc): The difference between two adjacent steady-state voltages relative to the nominal voltage. Dc must be =3%

Relative Voltage Change Characteristic (D(t)): The change in rms voltage, relative to the nominal voltage, as a function of time and between periods when the voltage is in a steady-state condition for at least 1 second. D(t) must not be > 3% for more than 200 milliseconds continuously during a voltage change event.

Maximum Relative Voltage change (Dmax): The difference between maximum and minimum rms values of the voltage change characteristic relative to the nominal voltage. Dmax must be =4%

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10.3 Voltage Fluctuations Test Setup Photo

< FRONT VIEW >



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10.4 Voltage Fluctuations Test Data

Model No : AP1100

RMS Voltage : 229.9 V RMS Current : 0.5 A
Real Power : 52.2 W Peak Current : 1.8 A
Apparent Power : 108.6 VA Frequency : 50.0 Hz

	Indicated Values	Limit	Pass(P) or Fail (F)
Pst	0.07	< 1.0	P
Plt	0.07	< 0.65	P
Dc	0.00%	< 3.3%	P
Dmax	0.00%	< 4%	P
D(t)	0.00%	< 3.3%	P

Pst : Short-term flicker indicator

Plt : Long-term flicker indicator

Dc : Relative steady state voltage change

Dmax : Maximum relative voltage change

D (t) : Voltage change

11. EN 61000-4-2 Electrostatic Discharge Test

Test standard	Model No.	Result
EN 61000-4-2	AP1100	A

The test results shall be classified on the basis of the operating conditions and the functional specifications of the equipment under test (EUT). As in the following, unless different specifications are given by product committees or product specifications:

Performance criterion:

A) The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

B) After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.

C) Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.

Function, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

The performance criteria requirement of the immunity test should be determined from consideration of the electrical characteristics and usage of EUT. For more detail about the performance criteria requirement, please refer to the Annex attached in the European Standard EN 55024: 1995 +A2: 2001.

11.1 Electrostatic Discharge Test Description

This standard relates to equipment, systems, sub-systems and peripherals which may be involved in static electricity discharges owing to environmental and installation conditions. such as low relative humidity, use of low-conductivity (artificial-fibre) carpets, vinyl garments, etc., which may exist in allocations classified in standards relevant to electrical and electronic equipment.

The test set-up shall consist of a wooden table, 0.8 m high standing on the ground reference plane. A horizontal coupling plane(HCP), 1.6 m x 0.8 m, shall be placed on the table. The EUT and cables shall be isolated from the coupling plane by an insulating support 0.5 mm thick .

A ground reference plane shall be provided on floor of the laboratory. It shall be metallic sheet of 0.25 mm minimum thickness. The minimum size of the reference plane is 1 m, the exact size depending on the dimensions of the EUT .

It shall project beyond the EUT or coupling plane by at least 0.5 m on all sides. and shall be connected to the protective grounding system.

In order to minimize the impact of environmental parameters on test results, the tests shall be carried out in climatic and electromagnetic reference conditions.

Climatic conditions

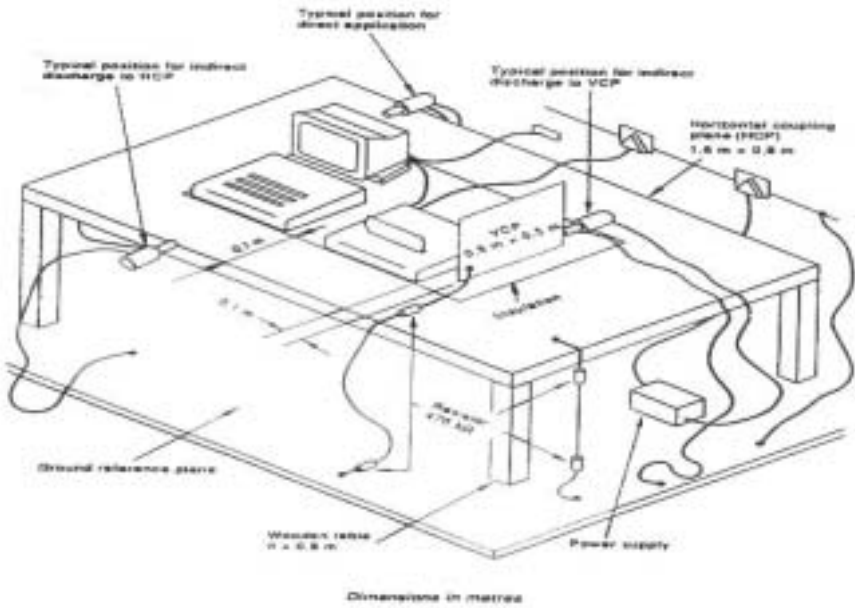
- ambient temperature: 15 °C to 35°C;
- relative humidity: 30 % to 60%
- atmospheric pressure: 86 KPa (860 mbar) to 106 KPa (1 060 mbar).

NOTE – Any other values are specified in the product specification.

Electromagnetic conditions

The electromagnetic environment of the laboratory shall not influence the test results.

11.2 Electrostatic Discharge Test Setup



- Example of test set-up for table-top equipment,
laboratory tests

11.3 Electrostatic Discharge Test Limits

Test levels

Contact discharge		Air discharge	
Level	Test voltage kv	Level	Test voltage
1	2	1	2
2	4	2	4
3	6	3	8
4	8	4	15
x ¹⁾	Special	x ¹⁾	Special

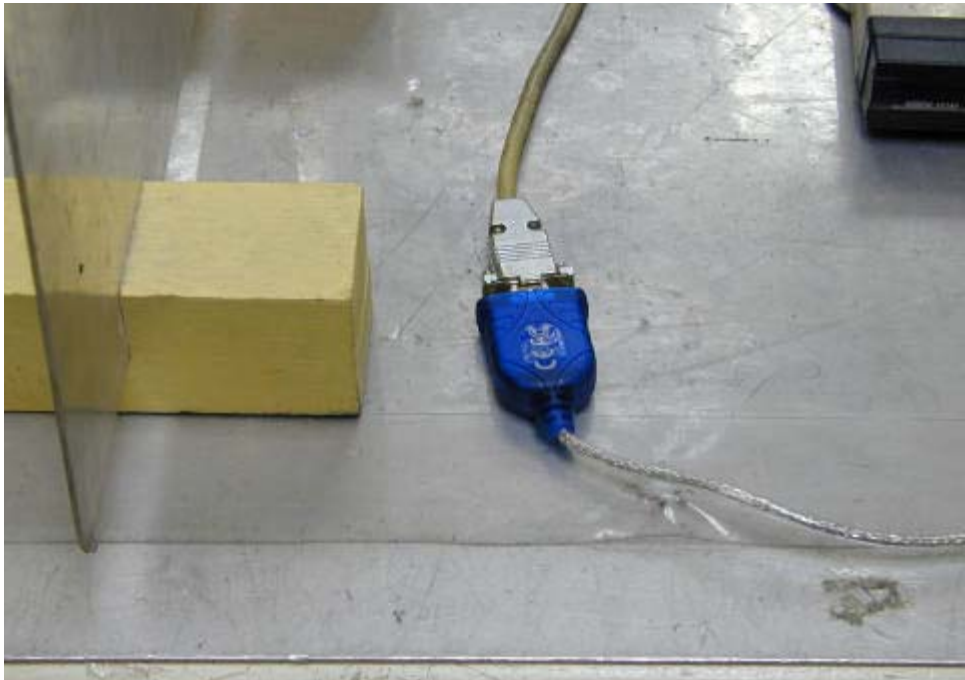
¹⁾ "x" is an open level . The level has to be specified in the dedicated equipment specification .

If higher voltages than those shown are specified , special test equipment may be needed .

11.4 Direct Discharge Test Drawing



Indirect Discharge Test Drawing



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11.5 Electrostatic Discharge Test Data (Direct Discharge)

Model No. : _____ AP1100 _____

Test Item : Direct Discharge		Instrument : NoiseKen ESS-100L															
Temperature : <u> 26 </u> °C		Relative Humidity : <u> 50 </u> %RH															
Storage Capacitor : 150 pf		Discharge Resistor : 330 Ohm															
Discharge Rate : < 1 / Sec																	
	Contact Discharge								Air Discharge								
	2 KV		4 KV		6 KV		8 KV		2 KV		4 KV		6 KV		8 KV		
	+	-	+	-	+	-	+	-	+	-	+	-	+	-	+	-	
1	P	P	P	P	/	/	/	/	P	P	P	P	P	P	P	P	
2	P	P	P	P	/	/	/	/	P	P	P	P	P	P	P	P	
3	P	P	P	P	/	/	/	/	P	P	P	P	P	P	P	P	
4	/	/	/	/	/	/	/	/	P	P	P	P	P	P	P	P	
5	/	/	/	/	/	/	/	/	P	P	P	P	P	P	P	P	
6	/	/	/	/	/	/	/	/	P	P	P	P	P	P	P	P	
7	/	/	/	/	/	/	/	/	P	P	P	P	P	P	P	P	
8	/	/	/	/	/	/	/	/	P	P	P	P	P	P	P	P	
9	/	/	/	/	/	/	/	/	P	P	P	P	P	P	P	P	
10	/	/	/	/	/	/	/	/	P	P	P	P	P	P	P	P	

1. " P " - - - - means the EUT function is correct during the test. _____

2. " / " - - - - no test. _____

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Electrostatic Discharge Test Data (Indirect Discharge)

Model No. : _____ AP1100 _____

Test Item : Indirect Discharge		Instrument : NoiseKen ESS-100L															
Temperature : <u>26</u> °C		Relative Humidity : <u>50</u> %RH															
Storage Capacitor : 150 pf		Discharge Resistor : 330 Ohm															
Discharge Rate : < 1 / Sec																	
	Contact Discharge								Air Discharge								
	2 KV		4 KV		6 KV		8 KV		2 KV		4 KV		6 KV		8 KV		
	+	-	+	-	+	-	+	-	+	-	+	-	+	-	+	-	
1	P	P	P	P	/	/	/	/	/	/	/	/	/	/	/	/	
2	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	
3	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	
4	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	
5	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	
6	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	
7	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	
8	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	
9	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	
10	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	/	

1. " P " - - - - means the EUT function is correct during the test. _____

2. " / " - - - - no test. _____

12. EN 61000-4-3 Radio-Frequency Electromagnetic Field Test

Test standard	Model No.	Result
EN 61000-4-3	AP1100	A

Field Strength : 3 V/M , Level 2 .

Modulation : AM 80 % , 1KHz . ON (YES) . OFF (___)

Start : 80 MHz , Stop : 1000 MHz . AC Power : 230 Vac

DC Power : N/A Vdc

The test results shall be classified on the basis of the operating conditions and the functional specifications of the equipment under test (EUT). As in the following, unless different specifications are given by product committees or product specifications:

Performance criterion:

A) The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

B) After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.

C) Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.

Function, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

The performance criteria requirement of the immunity test should be determined from consideration of the electrical characteristics and usage of EUT. For more detail about the performance criteria requirement, please refer to the Annex attached in the European Standard EN 55024: 1996 +A2: 2001.

12.1 Radio-Frequency Electromagnetic Field Test Description

Most electronic equipment is, in some manner, affected by electromagnetic radiation.

This radiation is frequently generated by such sources as the small hand-held radio transceivers that are used by operating, maintenance and security personnel, fixed-station radio and television transmitters, vehicle radio transmitters, and various industrial electromagnetic sources.

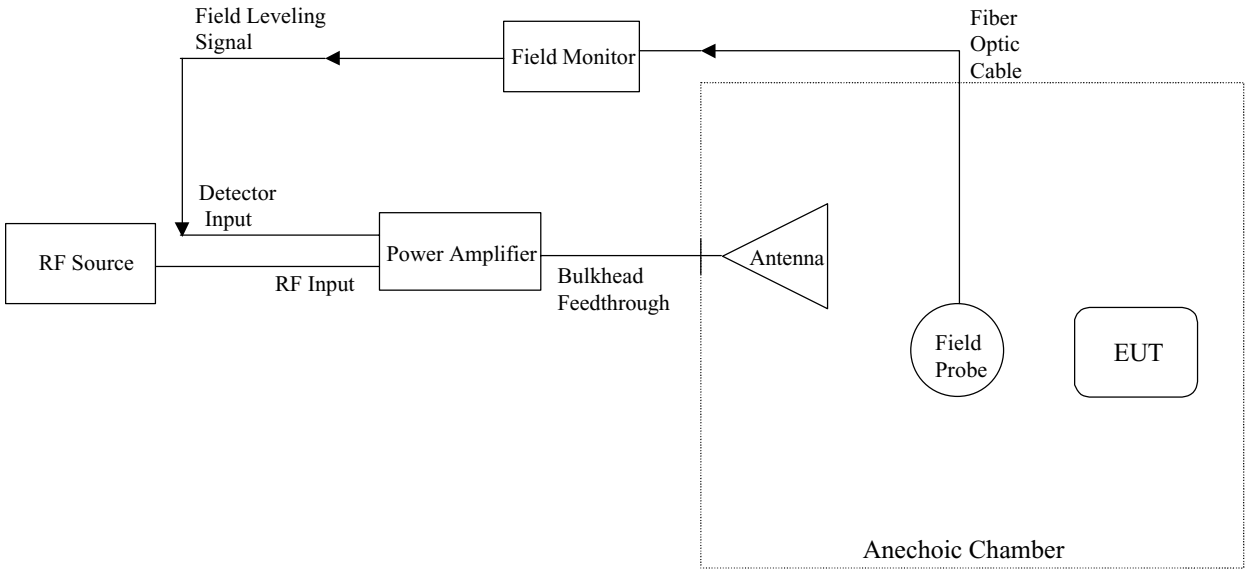
In addition to electromagnetic energy deliberately generated, there is also spurious radiation caused by devices such as welders, thyristors, fluorescent lights, switches operating inductive loads, etc. For the most part, this interference manifests itself as conducted electrical interference and, as such, is dealt with in other parts of this standard. Methods employed to prevent effects from electromagnetic fields will normally also reduce the effects from these sources.

The electromagnetic environment is determined by the strength of the electromagnetic field (field strength in volts per metre). The field strength is not easily measured without sophisticated instrumentation nor is it easily calculated by classical equations and formulae because of the effect of surrounding structures or the proximity of other equipment that will distort and/or reflect the electromagnetic waves.

All testing of equipment shall be performed in a configuration as close as possible to the installed case. Wiring shall be consistent with the manufacturer's recommended procedures, and the equipment shall be in its housing with all covers and access panels in place, unless otherwise stated.

If the equipment is designed to be mounted in a panel, rack or cabinet, it shall be tested in this configuration.

12.2 Radio-Frequency Electromagnetic Field Test Block Diagram



12.3 Radio-Frequency Electromagnetic Field Test Limits

Table 1 - Test levels

Level	Test field strength V/m
1	1
2	3
3	10
x	Special

NOTE – x is an open test level. This level may be given in the Product specification.

Table 1 gives details of the field strength of the unmodulated signal. For testing of equipment, this signal is 80 % amplitude modulate with a 1 KHz sinewave to simulate actual threats.

12.4 Radio-Frequency Electromagnetic Field Test Setup Photo

< FRONT VIEW >



13. EN 61000-4-4 Fast Transient Burst Test

Test standard	Model No.	Result
EN 61000-4-4	AP1100	A

The test results shall be classified on the basis of the operating conditions and the functional specifications of the equipment under test (EUT). As in the following, unless different specifications are given by product committees or product specifications:

Performance criterion:

- A) The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.**
- B) After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.**
During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.
- C) Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.**
Function, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

The performance criteria requirement of the immunity test should be determined from consideration of the electrical characteristics and usage of EUT. For more detail about the performance criteria requirement, please refer to the Annex attached in the European Standard EN 55024: 1995 +A2: 2001.

13.1 Fast Transient Bursts Test Description

The repetitive fast transient test is a test with bursts consisting of a number of fast transients, coupled into USB 2.0 4+1 PCI Host Card, control and signal ports of electrical and electronic equipment. Significant for the test are the short rise time, the repetition rate and the low energy of the transients.

The test shall be carried out on the basis of a test plan including verification of the performances of the EUT as defined in the technical specification.

Climatic conditions

The tests shall be carried out in standard climatic conditions in accordance with IEC 68-1:

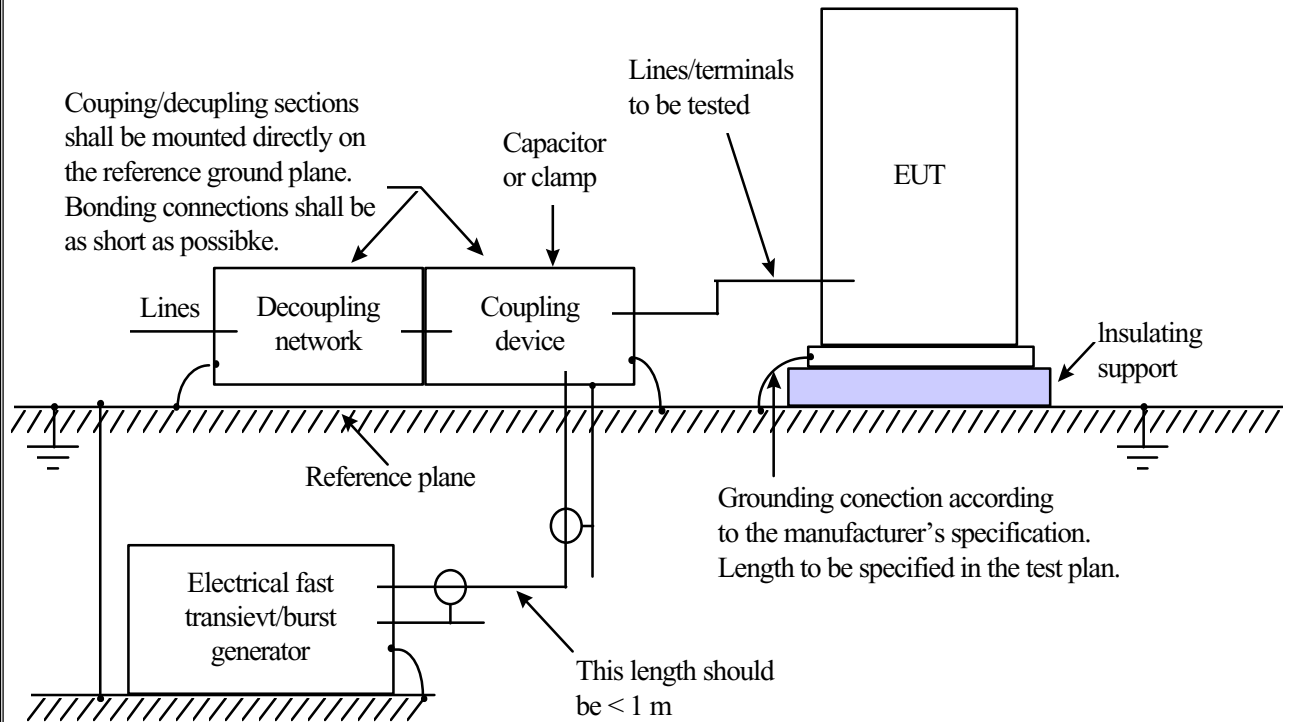
- ambient temperature: 15°C to 35°C
- relative humidity: 25% to 75%
- atmospheric pressure: 86kPa (860 mbar) to 106Kpa (1 060 mbar)

NOTE – Any other values are specified in the product specification.

Electromagnetic conditions

The electromagnetic conditions of the laboratory shall be such to guarantee the correct operation of the EUT in order not to influence the test results.

13.2 Fast Transient Burst Test Setup



Block-diagram for electrical fast transient/burst immunity test

13.3 Fast Transient Burst Test Limits

Test levels

Open-circuit output test voltage ($\pm 10\%$) and repetition rate of the impulses ($\pm 20\%$)				
Level	On power supply port, PE		On I/O (Input/Output) signal, data and control ports	
	Voltage peak kV	Repetition rate kHz	Voltage peak kV	Repetition rate kHz
1	0.5	5	0.25	5
2	1	5	0.5	5
3	2	5	1	5
4	4	2.5	2	5
x ¹⁾	Special	Special	Special	Special

¹⁾ "x" is an open level. The level has to be specified in the dedicated equipment specification.

13.4 Fast Transient Burst Test Setup Photo

< FRONT VIEW >



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REPORT NO. : E930592

13.5 Fast Transient Burst Test Data

MODEL NO. : _____ AP1100 _____

REGULATION : According to EN 61000-4-4 (1995+A2: 2001) Spec .

TEST RESULT

Temperature : 27 degree . Duration of tests : 1 min .
Relative Humidity : 53 % RH . Time between test : 60 second .
Pulse : 5 / 50 ns . AC Power : 230 Vac .
Burst : 15 ms / 300 ms . DC Power : N/A Vdc .

Voltage \ Polarity \ Test Point \ Mode \ Result		0.5 KV		1 KV		KV	
		+	-	+	-	+	-
Power Line	L	/	/	P	P	/	/
	N	/	/	P	P	/	/
	G	/	/	P	P	/	/
Signal Line Clamp Test		/	/	/	/	/	/

- Note :
1. "P" mean the EUT function is correct during the test .
 2. "F" - - - - Fail
 3. "/" - - - - no test

14. EN 61000-4-5 Surge Immunity Test

Test standard	Model No.	Result
EN 61000-4-5	AP1100	A

The test results shall be classified on the basis of the operating conditions and the functional specifications of the equipment under test (EUT). As in the following, unless different specifications are given by product committees or product specifications:

Performance criterion:

- A) The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.**
- B) After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.**
During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.
- C) Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.**
Function, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

The performance criteria requirement of the immunity test should be determined from consideration of the electrical characteristics and usage of EUT. For more detail about the performance criteria requirement, please refer to the Annex attached in the European Standard EN 55024: 1995 +A1: 2001.

14.1 Surge Immunity Test Description

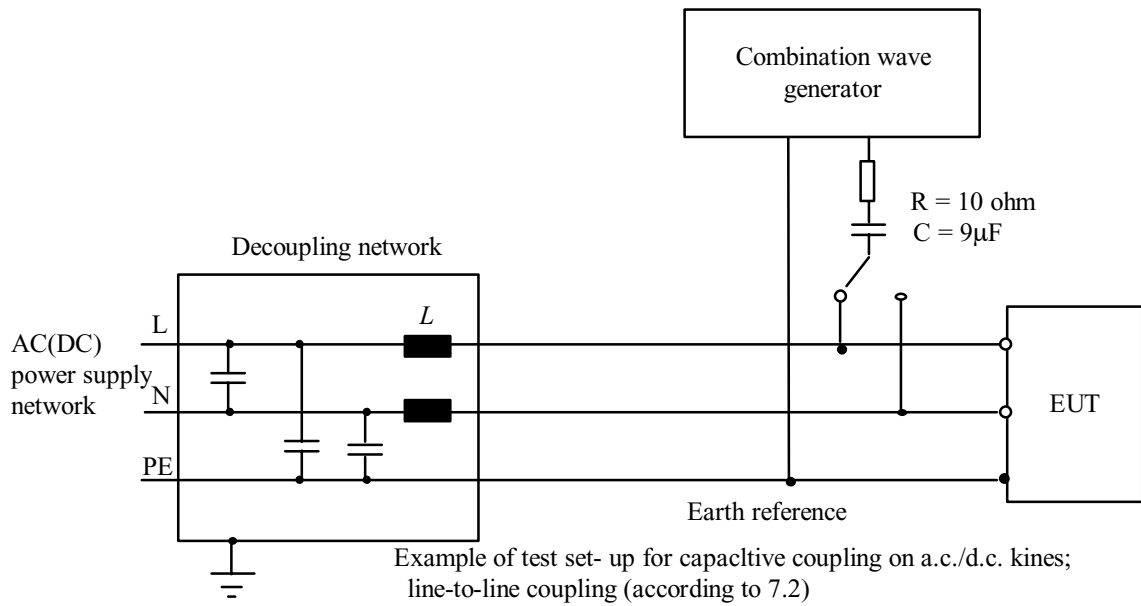
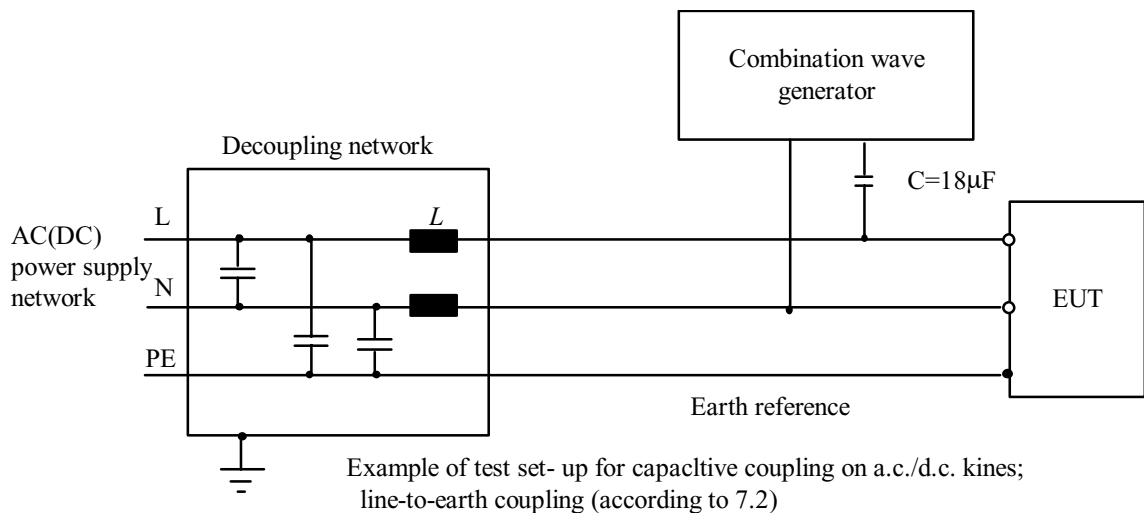
The task of the described laboratory test is to find the reaction of the EUT under specified operational conditions caused by surge voltages from switching and lightning effects at certain threat levels.

The following equipment is part of the test set-up :

- equipment under test (EUT);
- auxiliary equipment (AE);
- cables (of specified type and length);
- coupling device (capacitive or arrestors);
- test generator (combination wave generator, 1.2/50 μ s generator);
- decoupling network/protection devices;
- additional resistors, 10 ohm and 40 ohm

The surge is to be applied to the EUT USB 2.0 4+1 PCI Host Card terminals via the capacitive coupling network. Decoupling networks are required in order to avoid possible adverse effects on equipment not under test that may be powered by the same lines and to provide sufficient decoupling impedance to the surge wave so that the specified wave may be developed on the lines under test .

14.2 Surge Immunity Test Setup



14.3 Surge Immunity Test Limits

The preferential range of test levels is given in table 1.

Table 1-Test levels

Level	Open-circuit test voltage ±10 % kV
1	0.5
2	1.0
3	2.0
4	4.0
x	Special

NOTE - x is an open class . The level can be specified in the product specification .

14.4 Surge Immunity Test Setup Photo

< FRONT VIEW >



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REPORT NO. : E930592

14.5 Surge Immunity Test Data

MODEL NO : AP1100

TEST SETUP : According to EN 61000-4-5 (1995+A1: 2001)

TEST RESULT

Temperature : <u>27</u> °C		Relative Humidity <u>53</u> %RH								
Waveform : <u>1,2 x 50 μs</u>		Test rate : <u>15</u> sec								
Times <u>1</u> times / each condition		AC power <u>230</u> VAC								
\Phase		0	45	90	135	180	215	270	315	
\Voltage\Mode\Polarity\Result										
1KV	Line	+	P	P	P	P	P	P	P	P
	Neutral	-	P	P	P	P	P	P	P	P
2KV	Line	+	/	/	/	/	/	/	/	/
	Neutral	-	/	/	/	/	/	/	/	/
2KV	Line	+	P	P	P	P	P	P	P	P
	Ground	-	P	P	P	P	P	P	P	P
	Neutral	+	P	P	P	P	P	P	P	P
	Ground	-	P	P	P	P	P	P	P	P

- Note : 1. " P " means the EUT function is correct during the test
2. "/" no test

15. EN 61000-4-6 Immunity To Conducted Disturbances, Induced By Radio-Frequency Fields

Test standard	Model No.	Result
EN 61000-4-6	AP1100	A

The test results shall be classified on the basis of the operating conditions and the functional specifications of the equipment under test (EUT). As in the following, unless different specifications are given by product committees or product specifications:

Performance criterion:

A) The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

B) After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.

C) Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.

Function, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

The performance criteria requirement of the immunity test should be determined from consideration of the electrical characteristics and usage of EUT. For more detail about the performance criteria requirement, please refer to the Annex attached in the European Standard EN 55024: 1996 +A1: 2001.

15.1 Immunity To Conducted Disturbances, Induced By Radio-Frequency Fields Description

The EUT shall be placed on an insulating support, 0.1 m above the ground reference plane. For table-top equipment, the ground reference plane may be placed on a table (see figure) .

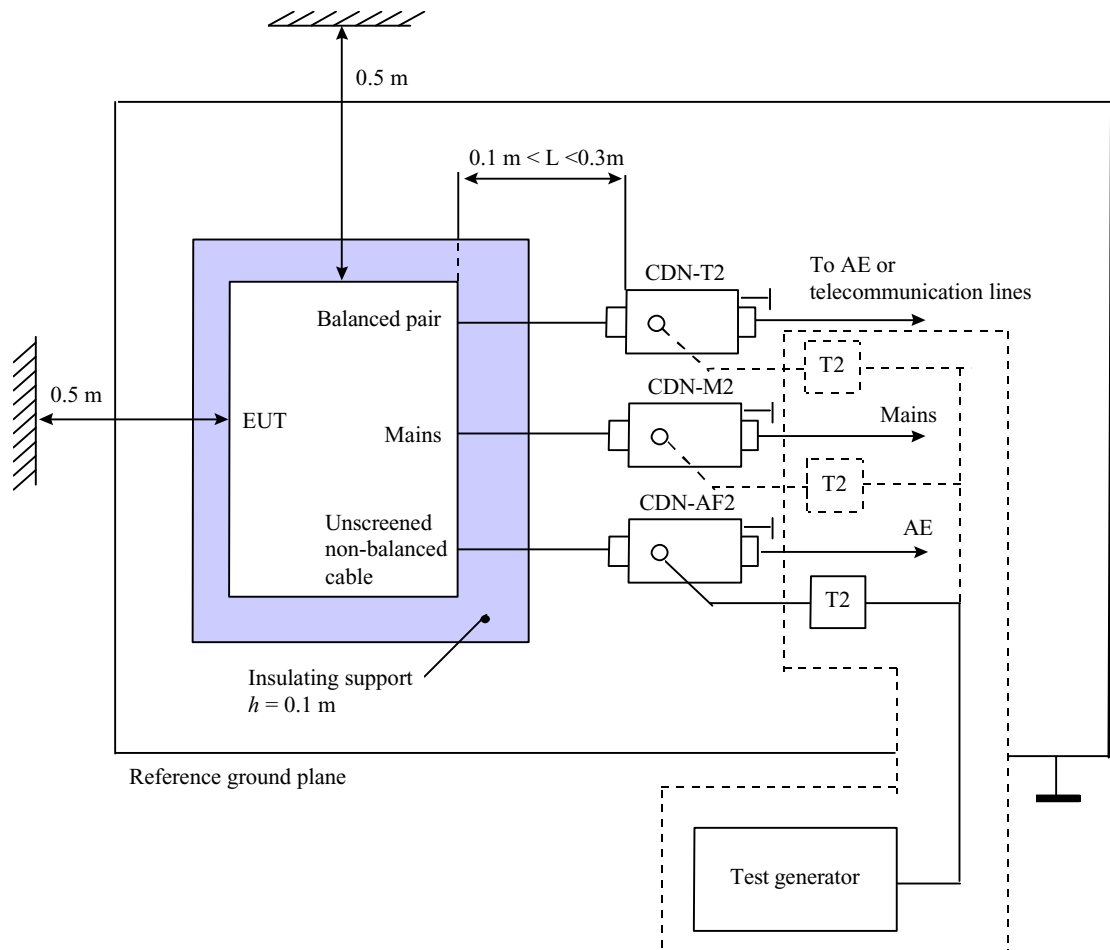
On all cables to be tested, coupling and decoupling devices shall be inserted. The coupling and decoupling devices shall be placed on the ground reference plane, making direct contact with it at about 0.1 m to 0.3 m from the EUT. The cables between the coupling and decoupling devices and the EUT shall be as short as possible and shall not be bundled nor wrapped. height above the ground reference plane shall be between 30 mm and 50 mm.

If the EUT is provided with other earth terminals, they shall, when allowed, be connected to the ground reference plane through the coupling and decoupling network CDN-M1, (i.e. the AE port of the CDN-M1 is then connected to the ground reference).

If the EUT is provided with a keyboard or hand-held accessory, then the artificial hand shall be placed on this keyboard or wrapped around the accessory and connected to the ground reference plane.

Auxiliary equipment (AE) required for the defined operation of the EUT according to the specifications of the product committee, e.g. communication equipment, modem, printer, sensor, etc., as well as auxiliary equipment necessary for ensuring any data transfer and assessment of the functions, shall be connected to the EUT through coupling and decoupling devices. However, as far as possible the number of cables to be tested should be limited by restricting attention to the representative functions.

15.2 Immunity To Conducted Disturbances, Induced By Radio-Frequency Fields Setup



NOTE - The EUT clearance from any metallic obstacles shall be at least 0.5 m .
 All non-excited input ports of the CDNs shall be terminated by 50 ohm loads.

Example of test set-up with a single-unit system
 for class II safety equipment (see IEC 536)

15.3 Immunity To Conducted Disturbances, Induced By Radio-Frequency Fields Test Limits

No tests are required for induced disturbances caused by electromagnetic fields coming from intentional RF transmitters in the frequency range 9 kHz to 150 kHz,
The open-circuit test levels (e.m.f.) of the unmodulated disturbing signal, expressed in r.m.s., are given in table 1. The test levels are set at the EUT port of the coupling and decoupling devices. For testing of equipment, this signal is 80% amplitude modulated with a 1 kHz sine wave to simulate actual threats.

Table1 – Test levels

Frequency range 150 kHz – 80MHz		
Level	Voltage level (e.m.t.)	
	Uo [dB(μ V)]	Uo[V]
1	120	1
2	130	3
X ¹⁾	140	10
	special	

¹⁾ X is an open level.

15.4 Immunity To Conducted Disturbances, Induced By Radio-Frequency Fields Test Setup Photo

< FRONT VIEW >



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REPORT NO. : E930592

15.5 Immunity To Conducted Disturbances, Induced By Radio-Frequency Fields Test Data

MODEL NO. : AP1100

REGULATION : EN 61000-4-6 (1996+A1: 2001)

TEST RESULT

Temperature : 27 degree , Relative Humidity : 53 % RH
Start : 0.15 MHz , Stop : 80 MHz , Power : AC 230V
Modulation : AM 80 % , 1kHz. ON (YES) , OFF (____)
Output impedance : 50 ohm , Source impedance : 150 ohm
Performance criterion : A

Test Ports	Frequency(MHz) Range	EUT Condition	1V(rms) Field strength	3V(rms) Field strength
Input / Output a. c. power	0.15 - - - - - 80	NORMAL	/	P
Input / Output d. c.	0.15 - - - - - 80	NORMAL	/	/
Signal lines Control lines	0.15 - - - - - 80	NORMAL	/	/

Note : 1. " P " mean the EUT function is correct during the test.

2. " / " no test.

16. EN 61000-4-8 Power Frequency Magnetic Field Immunity Test

Test standard	Model No.	Result
EN 61000-4-8	AP1100	A

(A) Test instruments :

- HAEFELY&TRENCH magnetic field tester MAG100.1
- HAEFELY&TRENCH coil with clamp 1m x 1m
- HAEFELY&TRENCH support with castors height 2m

(B) Laboratory reference conditions :

- Temperature : 26 °C
- relative humidity : 50 %
- atmospheric pressure : 95 kPa
- electromagnetic : 10 dB below the select test level

(C) Test level : level 1 , 1 A/m

The test results shall be classified on the basis of the operating conditions and the functional specifications of the equipment under test (EUT). As in the following, unless different specifications are given by product committees or product specifications:

Performance criterion:

A) The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

B) After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

During the test, degradation of performance is allowed. However, no change of operating state or stored data is allowed to persist after the test.

C) Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.

Function, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be lost.

The performance criteria requirement of the immunity test should be determined from consideration of the electrical characteristics and usage of EUT. For more detail about the performance criteria requirement, please refer to the Annex attached in the European Standard EN 55024: 1993 +A1: 2001.

16.1 Power Frequency Magnetic Field Immunity Test Description

The magnetic fields to which equipment is subjected may influence the reliable operation of equipment and systems.

The following tests are intended to demonstrate the immunity of equipment when subjected to power frequency magnetic fields related to the specific location and installation condition of the equipment (e.g. proximity of equipment to the disturbance source).

The power frequency magnetic field is generated by power frequency current in conductors or, more seldom, from other devices (e.g. leakage of transformers) in the proximity of equipment.

As for the influence of nearby conductors, one should differentiate between:

- the current under normal operating conditions, which produces a steady magnetic field, with a comparatively small magnitude;
- the current under fault conditions which can produce comparatively high magnetic fields but of short duration, until the protection devices operate (a few milliseconds with fuses, a few seconds for protection relays).

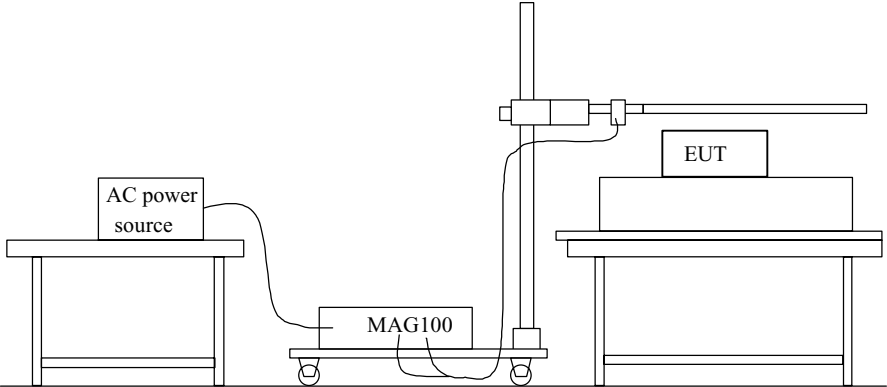
The test with a steady magnetic field may apply to all types of equipment intended for public or industrial low voltage distribution networks or for electrical plants.

The test with short duration magnetic field related to fault conditions, requires test levels that differ from those for steady state conditions; the highest values apply mainly to equipment to be installed in exposed places of electrical plants.

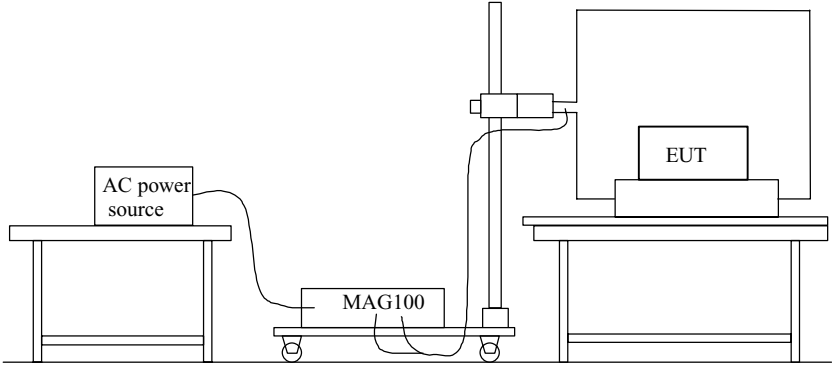
The test field waveform is that of power frequency.

In many cases (household areas, sub-stations and power plant under normal conditions), the magnetic field produced by harmonics is negligible. However, in very special cases like heavy industrial areas (large power convectors, etc.) they occur, and will be considered in a future revision of this standard.

16.2 Power Frequency Magnetic Field Immunity Test Setup



• Vertical magnetic field drawing



• Horizontal magnetic field drawing

16.3 Power Frequency Magnetic Field Immunity Test Limits

Table 1-Test levels for continuous field

Level	Magnetic field strength A/m
1	1
2	3
3	10
4	30
5	100
x ¹⁾	special

NOTES

1 – “x” is an open level. This level can be given in the product specification.

Table 2 – Test levels for short duration: 1 s to 3 s

Level	Magnetic field strength A/m
1	n.a. ²⁾
2	n.a. ²⁾
3	n.a. ²⁾
4	300
5	1000
x ¹⁾	special

NOTES

1 – “x” is an open level. This level, as well the duration of the test, can be given in the product specification.

2 – “n.a.” = not applicable

16.4 Power Frequency Magnetic Field Immunity Test Setup Photos

< VERTICAL VIEW >



< HORIZONTAL VIEW >



17. EN 61000-4-11 Voltage Dips, Short Interruptions And Voltage Variations Immunity Tests

17.1 Voltage Dips,short Interruptions And Voltage Variations Immunity Tests Description

Electrical and electronic equipment may be affected by voltage dips, short interruptions or voltage variations of power supply.

Voltage dips and short interruptions are caused by faults in the network, in installations or by a sudden large change of load. In certain cases, two or more consecutive dips or interruptions may occur. Voltage variations are caused by the continuously varying loads connected to the network. Before starting the test of a given equipment, a test plan shall be prepared.

It is recommended that the test plan shall comprise the following items :

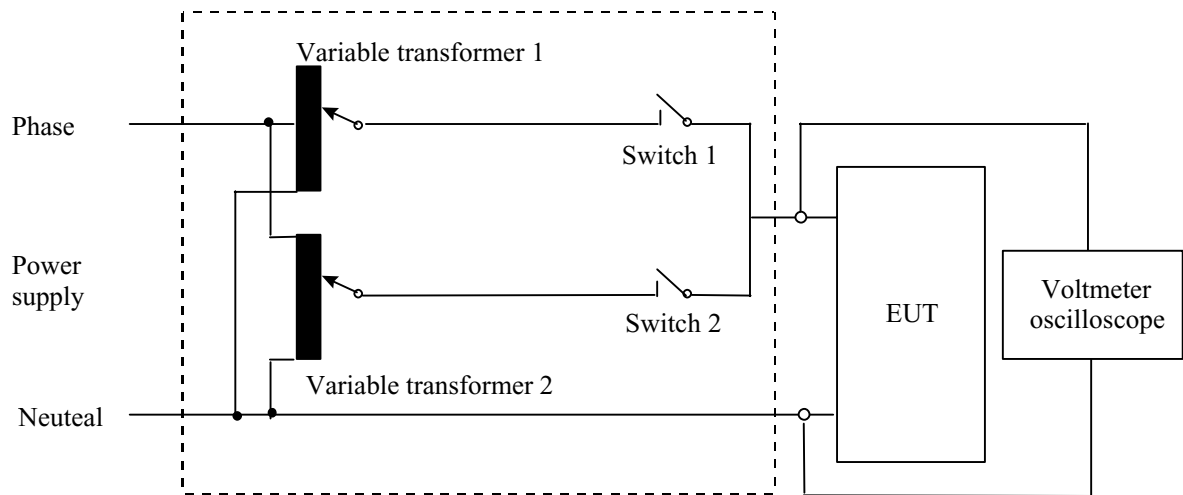
- the type designation of the EUT;
- information on possible connections (plugs, terminals, etc.) and cables, and peripherals;
- input power port of equipment to be tested;
- representative operational modes of the EUT for the test;
- performance criteria used and defined in the technical specifications;
- operational mode(s) of equipment;
- description of the test set-up.

If the actual operating signal sources are not available to the EUT, they may be simulated.

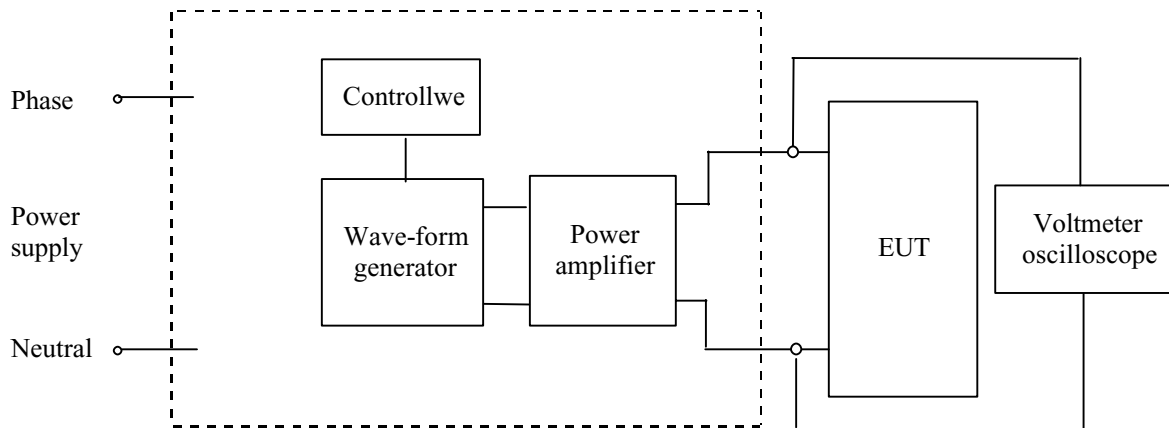
For each test any degradation of performance shall be recorded.

The monitoring equipment should be capable of displaying the status of the operational mode of the EUT during and after the tests. After each group of tests a full functional check shall be performed.

17.2 Voltage Dips, short Interruptions And Voltage Variations Immunity Tests Setup



Schematic of test Instrumentation for voltage dips and short interruptions using variable transformers and seitches



Schematic of test instrumentation for voltage dips, short interruptions and variations using power amplifier

17.3 Voltage Dips, short Interruptions And Voltage Variations Immunity Tests Limits

Preferred test levels and durations for
 voltage dips and short interruptions

Test level % U_T	Voltage dip and short interruptions % U_T	Duration (in period)
0	100	0.5*
40	60	1
70	30	5
		10
		25
		50
		x

* For 0.5 period, the test shall be made in positive and negative polarity, i.e. starting at 0° and 180°, respectively .

NOTES

- 1 One or more of the above test levels and durations may be chosen .
- 2 If the EUT is tested for voltage dips of 100%, it is generally unnecessary to test for other levels for the same durations. However, for some cases (safeguard systems or electromechanical devices) it is not true. The product specification or product committee shall give an indication of the applicability of this note .
- 3 "x" is an open duration. This duration can be given in the product specification. Utilities in Europe have measured dips and short interruptions of duration between 1/2 a period and 3 000 periods, but duration less than 50 periods are most common.
- 4 Any duration may apply to any test level .

17.4 Voltage Dips, short Interruptions And Voltage Variations Test Setup Photo

< FRONT VIEW >



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REPORT NO. : E930592

**17.5 Voltage Dips, short Interruptions And Voltage Variations
Immunity Tests Data**

MODEL NO. : _____ AP1100 _____

REGULAR : EN 61000-4-11 (1994+A1: 2001)

TEST RESULT : Test Voltage **230Vac**

	Test Level %U _T	Duration (ms)	Performance Criterion
Voltage dips	>95	10	A
	30	500	A
Voltage interruptions	>95	5000	C

U_T is the rated voltage for the equipment.

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18. The List of Test Instruments

Test Mode	Instrument	Model No.	Serial No.	Next Cal. Date	Cal. Interval
Conduction (No.2)	HP Spectrum	8591A	3225A03039	June 09, 2005	1Year
	R & S LISN(EUT)	ESH2-Z5	831886/004	Apr. 25, 2005	1Year
	Kyoritsu LISN(2nd)	KNW-242	8-837-7	N/A	N/A
	RF Cable	No.4	N/A	Feb. 19, 2005	1Year
Radiation (OP No.3)	R & S Receiver	ESBI	845658/003	July 28, 2005	1Year
	Schaffner Pre-Amp.	CPA-9232	1012	Aug. 20, 2005	1Year
	SCJWARZBECL Antenna	VULB9161	D-69250	May 19, 2005	1Year
	COM-Power Horn Ant.	AH-118 (1GHz~18GHz)	10095	May 25, 2005	1Year
	RF Cable	No.2	N/A	Feb. 19, 2005	1Year
	SCHWARZBECK Precision Dipole Ant.	VHAP (30MHz~1GHz)	970+971 953+954	June 26, 2006	3Year
	R & S Signal Generator	SMY01	829846/038	Feb. 16, 2005	2Year

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Test Mode	Test item	Instrument	Model No.	Serial No.	Next Cal. Date	Cal. Interval
EMS (NO.1)	4-2	ESD Test System	ESS-100L (A)TC-815D	4099C01970	July 14, 2005	1Year
	4-3	Comtest G-Strip	G-320	CC112-0008	Oct. 01, 2005	2Year
	4-4	KeyTek EFT Noise Generator	CE-40	9508266	Jane 27, 2005	2Year
	4-5	HAEFELY Surge Tester	PSURGE 4	083665-17	Dec. 18, 2004	2Year
	4-8	HAEFELY Magnetic Field	MAG 100.1	083858-04	Dec. 26, 2004	2Year
	4-11	HAEFELY Line Interference Tester	PLINE 1610	083732-01	Dec. 19, 2004	2Year
	4-3 4-6	HP Signal Generator	8648A	3619U00426	Sep. 14, 2005	1Year
	3-2 3-3	HP Harmonic/ Flicker Test System	6842A	3531A-00141	Dec. 19, 2004	2Year

19. EUT Photos

MODEL NO.: AP1100

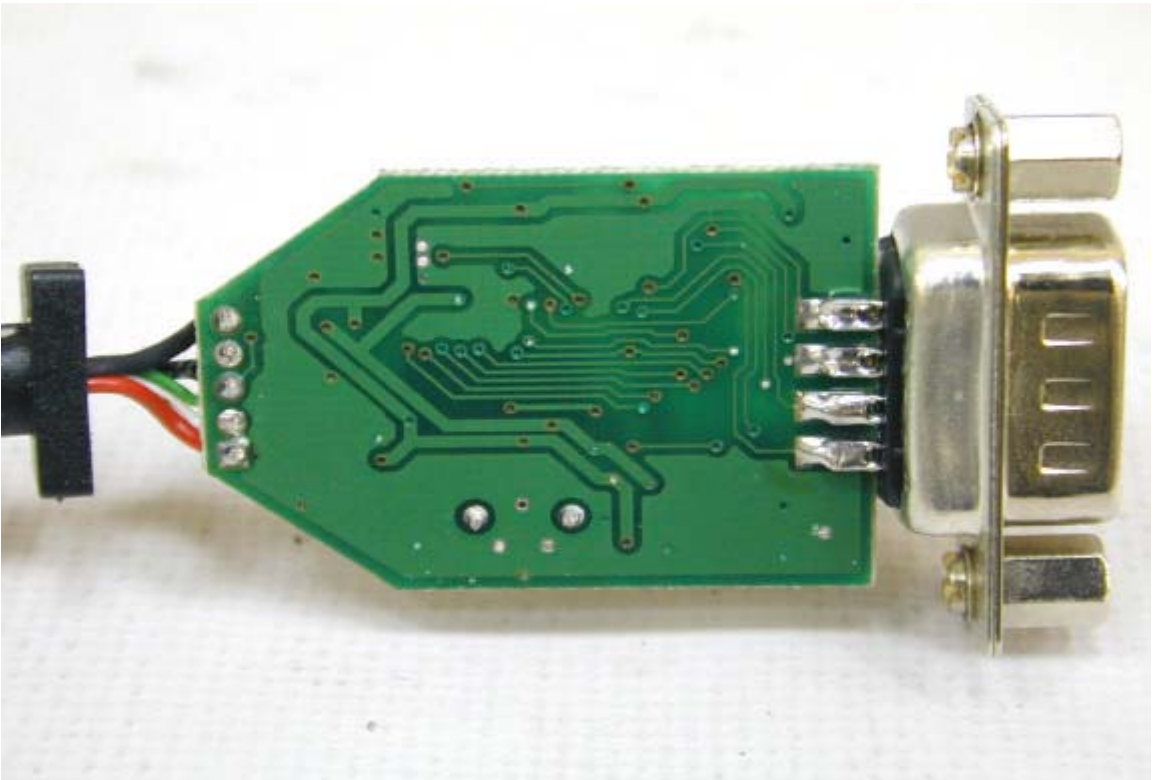


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REPORT NO. : E930592



VERIFICATION

of conformity with European EMC Directive

No. E930592

Document holder: GOOD WAY TECHNOLOGY CO., LTD.
Type of equipment: USB Serial Adapter
Type designation: AP1100

A sample of the equipment has been tested for CE-marking according to the EMC Directive, 89/336/EEC. & 92/31/EEC & 93/68/EEC *Standard(s) used for showing compliance with the essential requirements of the directive:*

EMC Standard(s):

EN 55022: 1998+A1: 2000

EN 61000-3-2: 2000

EN 61000-3-3:1995+A1: 2001

Class B

EN 55024: 1998+A1: 2001

EN 61000-4-2: 1995+A2: 2001

EN 61000-4-3: 1996+A2: 2001

EN 61000-4-4: 1995+A2: 2001

EN 61000-4-5: 1995+A1: 2001

EN 61000-4-6: 1996+A1: 2001

EN 61000-4-8: 1993+A1: 2001

EN 61000-4-11: 1994+A1: 2001

Performance Criterion

A

A

A

A

A

A

The referred test report(s) show that the product fulfills the requirements in the EMC Directive for CE marking. On this basis, together with the manufacturer's own documented production control, the manufacturer (or his European authorized representative) can in his EC Declaration of Conformity verify compliance with the EMC Directive.

Signed for and on behalf of
PEP Testing Laboratory



M. Y. Tsui

Date: SEP. 14, 2004

M. Y. Tsui / President

Declaration of Conformity

The following

Applicant : **GOOD WAY TECHNOLOGY CO., LTD.**

Equipment : **USB Serial Adapter**

Model No. : **AP1100**

Report No. : **E930592**

is herewith confirmed to comply with the requirements set out in the Council Directive on the Approximation of the Laws of the Member States relating to Electromagnetic Compatibility(89/336/EEC) and the amendments in the Council Directive 92/31/EEC, 93/68/EEC.

For the evaluation of above mentioned Directives, the following standards were applied:

- 1) EN 55022: 1998+A1 : 2000 Class B
- 2) EN 61000-3-2 : 2000
- 3) EN 61000-3-3 : 1995+A1: 2001
- 4) EN 55024 : 1998+A1 : 2001
 - EN 61000-4-2 : 1995+A2: 2001
 - EN 61000-4-3 : 1996+A2: 2001
 - EN 61000-4-4 : 1995+A2: 2001
 - EN 61000-4-5 : 1995+A1: 2001
 - EN 61000-4-6 : 1996+A1: 2001
 - EN 61000-4-8 : 1993+A1: 2001
 - EN 61000-4-11 : 1994+A1: 2001

The following manufacturer is responsible for this declaration:

GOOD WAY TECHNOLOGY CO., LTD.

**3F, NO. 135, LANE 235, PAU CHIAO RD., HSIN TIEN,
TAIPEI COUNTY,
TAIWAN, R. O. C.**

TAIWAN / SEP. 14, 2004

Place and Date

Signature of responsible Person